

Basic Laboratory Instrumentation

Lecture #2
Electronic measurements
Alessandro Pozzebon

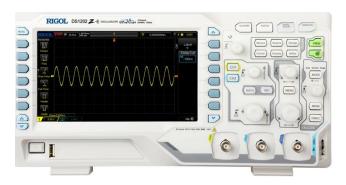


Basic instrumentation

Oscilloscope

Signal Generator

Digital multimeter

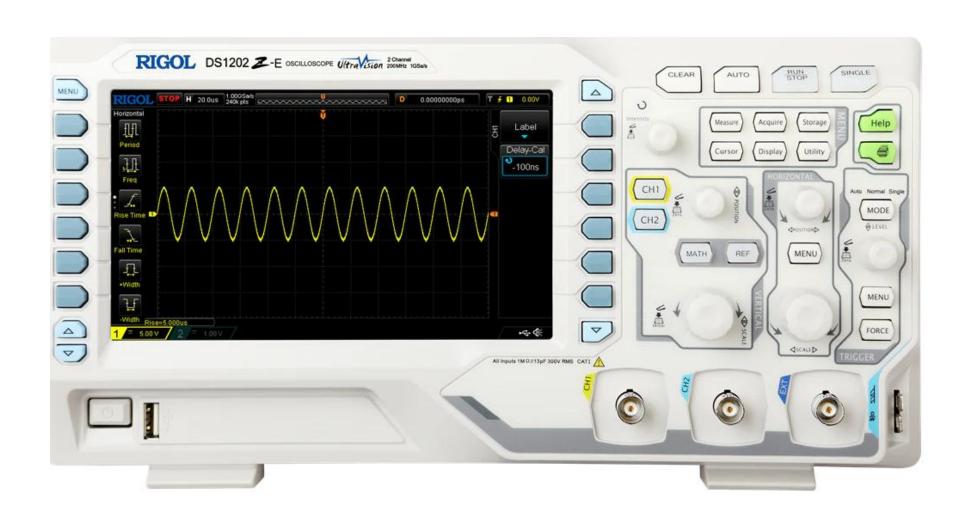






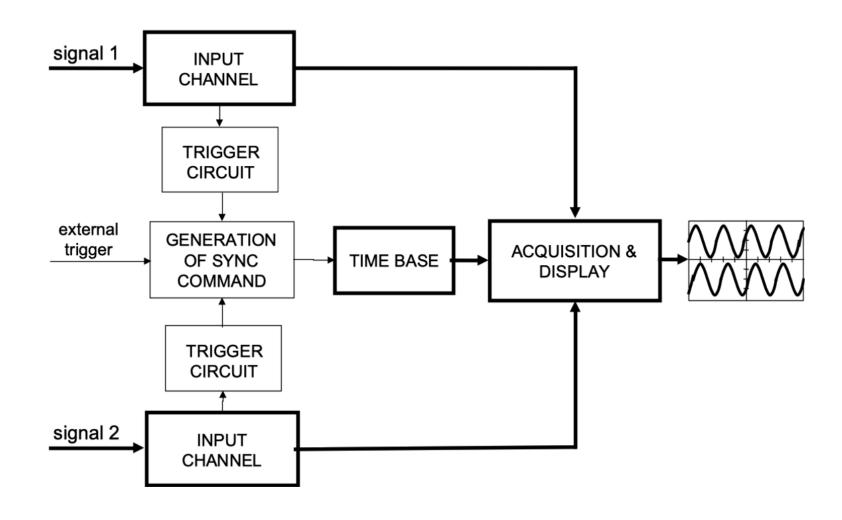


Oscilloscope



- Waveform analysis: the accurate measurement of signal behaviour
 - Observe
 - Measure
 - Compare
- Diagnostics: checking a system operation to detect possible anomalies and signal variations
- Finite observation interval
 - Synchronization
- Simultaneous acquisition of **2-4 signals**

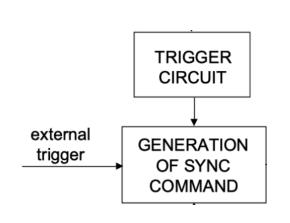
Oscilloscope Functional scheme





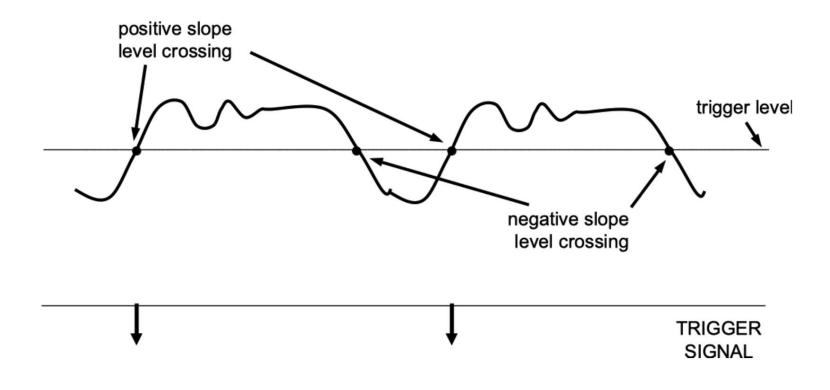
- Amplification and attenuation
- Bandwidth
 - From less than 100 MHz to several GHz
- Input impedance → as high as possible
 - Parallel of a resistance $R=1\ M\Omega$ and a capacitance in the order of ten pF

Oscilloscope Functional scheme



- Determine reference points to synchronize the instrument
- Trigger event: crossing of a preset voltage level
- Synchronization command: can combine multiple conditions and inputs
- External trigger

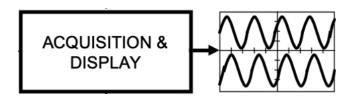
Oscilloscope Functional scheme



- Internal time reference
- Measurement of time intervals
- Observation interval length from few ns to several s
- Calibrated reference
- Internal instrument clock
- Crystal oscillator with relative uncertainty in the order of 10^{-4} to 10^{-6}

TIME BASE

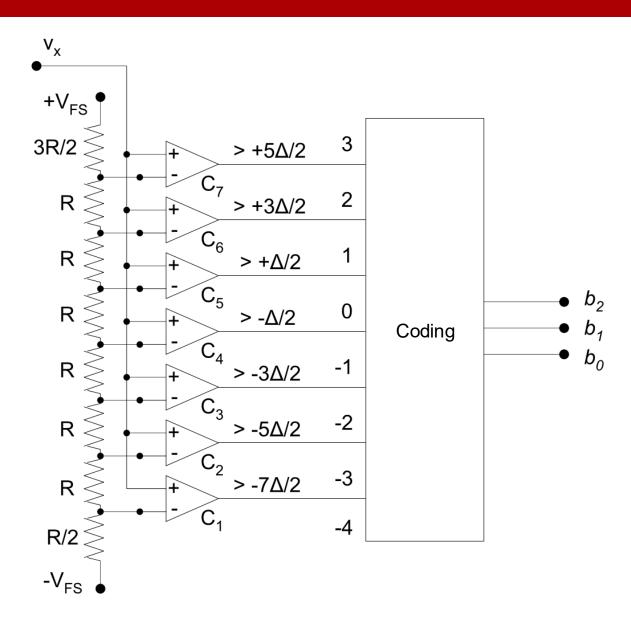
- Digital Sampling Oscilloscope (DSO)
- High speed data and acquisition system
- Analog-to-Digital Converter (ADC)
- Computing capabilities for digital signal processing
- Direct measurements and signal analysis





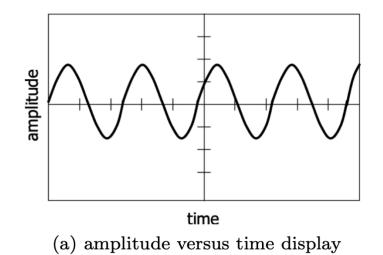
Oscilloscope Analogue to Digital conversion

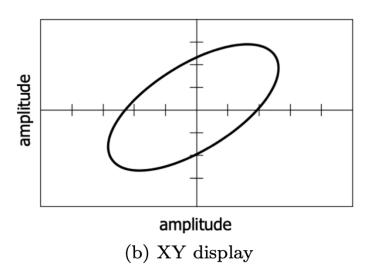
Flash ADC



Oscilloscope: visualization

- x-t display (voltage per division vs time per division)
 - Time base
- x-y display (voltage per division vs voltage per division)
 - Implicit time variable

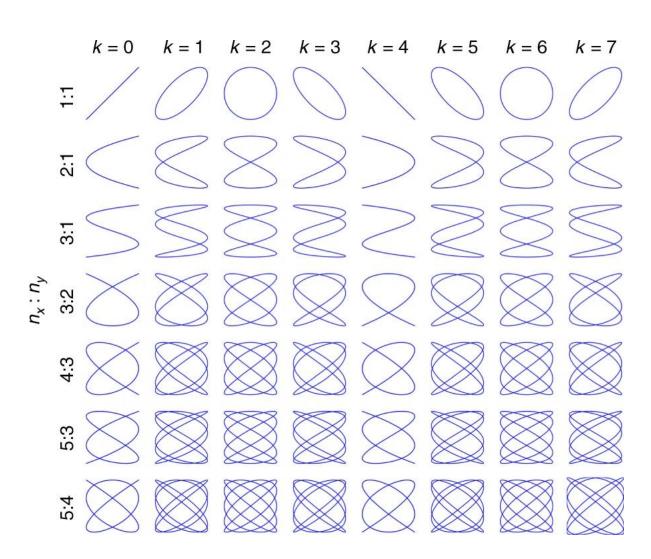






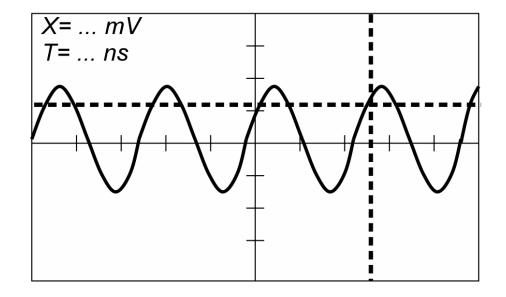
Oscilloscope: visualization

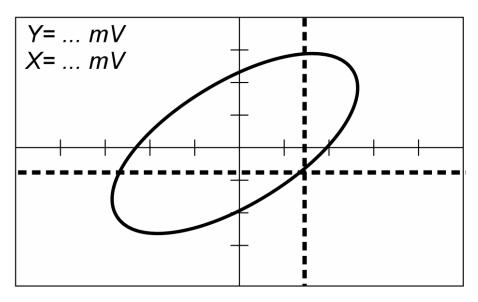
Lissajous curves



Oscilloscope: visualization

- Grid (divisions)
- Cursors
- Scale factors (voltage per division, time per division)





Amplitude uncertainty:

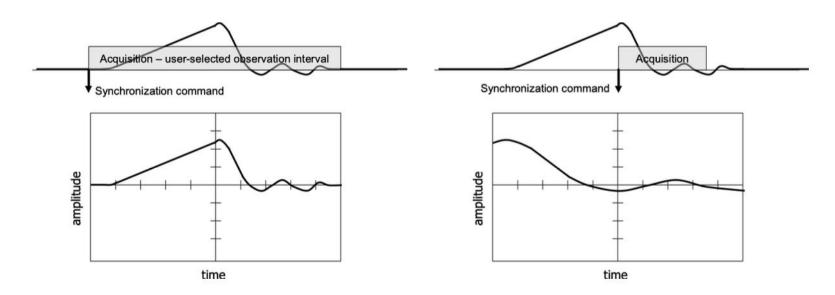
- Lower bound → ADC resolution
- 2^b quantization levels for a b bit ADC
- Input range → height of the oscilloscope grid
- Uncertainty: 1/ 2^b of the full scale value \rightarrow lower than 1%
- Noise and calibration uncertainty \rightarrow around 1%

• Time base uncertainty:

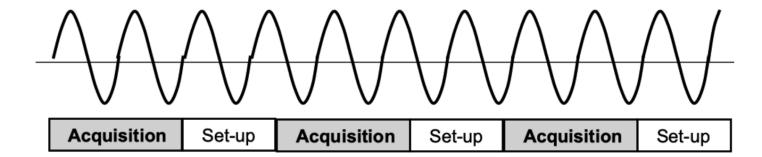
- Reciprocal of the **instrument memory depth**: N samples $\rightarrow 1/N$ uncertainty
- Further limited by graphical resolution \rightarrow 600 x 1000 pixels, 1/1000 resolution
- Clock uncertainty

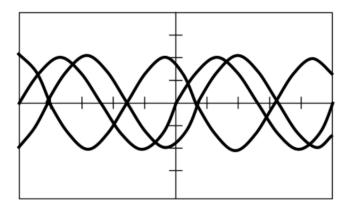
- Horizontal scale factor → set observation interval length
- **Vertical scale factor** → set the amplitude scale
- **Trigger** → Synchronize signal acquisition

Non repetitive signal → acquisition is triggered by a synchronization command

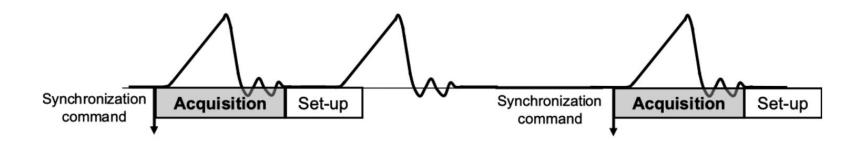


- Acquisition phase t_A
- Setup-up phase t_B
 - Minimum interval = $t_A + t_B$

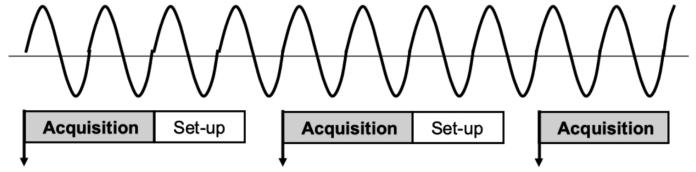


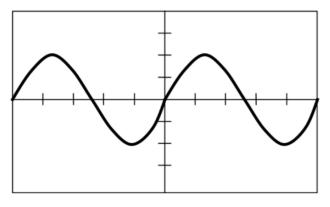


- Acquisition phase t_A
- Setup-up phase t_B
 - Minimum interval = $t_A + t_B$
- Wait phase t_c

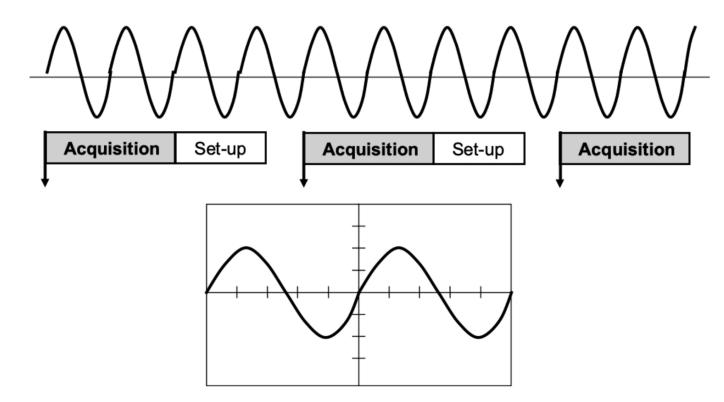


- Acquisition phase t_A
- Setup-up phase t_B
 - Minimum cycle length = $t_A + t_B$
- Wait phase t_c
 - Total cycle length = $t_A + t_B + t_C$
- Signal period T
 - $t_A + t_B + t_C = MT$ with $M \in \mathbf{Z}$





- Signal period T
 - $t_A + t_B + t_C = MT$ with $M \in \mathbf{Z}$
- Trace update rate
 - $1/t_A + t_B + t_C$
- Acquisition efficiency
 - $0 < t_A / t_A + t_B + t_C < 1$







- Test inputs for measurements
- **Different waveforms** according to the specific test

- Analog signals → different waveforms (multi-sine combinations)
- **Digital signals** → transitions between two levels

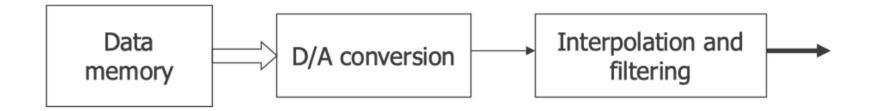
- Linear systems → Sinewaves
 - Same frequency as the input
 - Different amplitude and phase

- Sinewave generator
 - Adjustable amplitude and frequency
 - Low harmonic content
 - Stable output frequency
 - Stable output amplitude
 - Limited number of low level spurious components

Specialized laboratory equipment

- Waveform generator
 - Different generable signals: sinusoidal, triangular, square and ramp waveforms

- More flexibility, less accuracy...
- Sampling Shannon theorem \rightarrow continuous-time reconstruction (band limited signal)
- Digital Samples \rightarrow Analog samples \rightarrow Interpolation Low-pass filtering



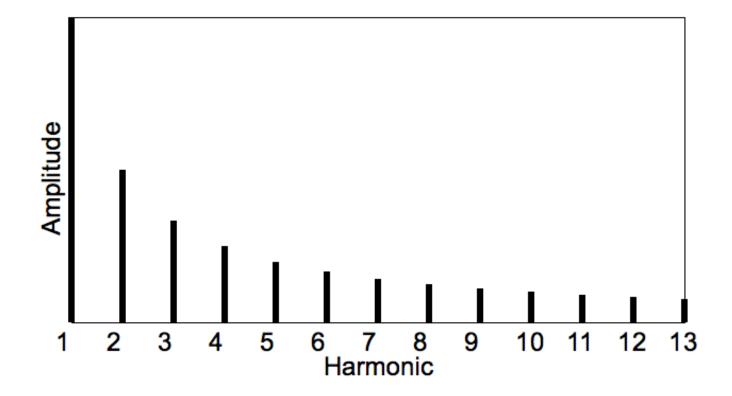
- Arbitrary Waveform Generator (AWG)
 - Signal stability
 - Good frequency and amplitude resolution
 - Low harmonic distortion
 - Easy generation of complex waveforms
 - Digital memory for the writing of samples related to arbitrary waveforms
 - Common waveforms stored permanently \rightarrow faster standard operations (changing amplitude and frequency)



- Arbitrary Waveform Generator (AWG)
 - Voltage source
 - 50 Ω output impedance \rightarrow adaptation to the characteristic impedance of coaxial cables
 - Actual voltage indication only in case of maximum power transfer ($R_G = R_L$)
 - Connection of an AWG to the oscilloscope → High impedance load

Sinewave

- Spectrum composed of a single spectral line (with its frequency image)
- Possible harmonic components



Sinewave

- Spectrum composed of a single spectral line (with its frequency image)
- Possible harmonic components
- Total Harmonic Distortion (THD): typical values < -70 dB

$$\frac{\sqrt{V_{RMS_2}^2 + V_{RMS_3}^2 + \cdots}}{V_{RMS_1}}$$

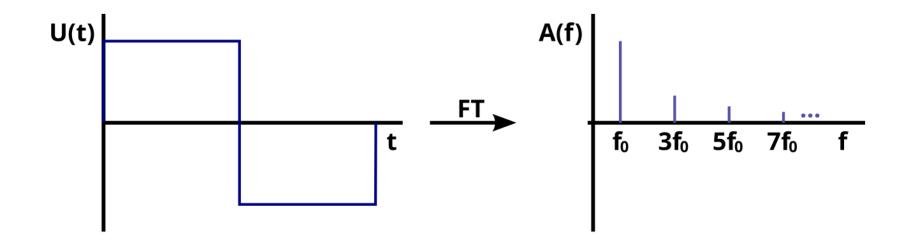
Signal to Noise and Distortion (SINAD): typical values > 70 dB

$$\frac{V_{RMS_{-1}}}{\sqrt{V_{RMS_{-2}}^2 + V_{RMS_{-3}}^2 + \dots + N}}$$

Square Wave

- Spectral lines at the fundamental frequency and its integer multiples (harmonics)
- Fundamental frequency and harmonic components at **odd multiples**

$$\left| \frac{A_k}{A_1} \right| = \begin{cases} \frac{1}{k} & \text{for } k \text{ odd} \\ 0 & \text{for } k \text{ even} \end{cases}$$



Square Wave

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Asymmetries in the lengths of level → duty cycle D not 50%

$$\left| \frac{A_k}{A_1} \right| = \frac{1}{k} \frac{\sin \pi k D}{\sin \pi D}$$

• In general D \cong 0.5 \rightarrow D = $\frac{1}{2}(1 + 2\delta)$

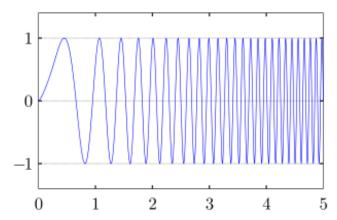
$$\left| \frac{A_k}{A_1} \right| = \begin{cases} \frac{1}{k} & \text{for } k \text{ odd} \\ \pi \delta & \text{for } k \text{ even} \end{cases}$$

Frequency sweep or chirp

Sinewave whose frequency varies linearly with time in a certain interval

$$f(t) = f_1 + \frac{f_2 - f_1}{T_{sweep}} t$$
 with $0 \le t \le T_{sweep}$

- Spectrum with constant amplitude for $f_1 \le f \le f_2$
- Measuring the **system response G(f)** for a certain frequency interval. |Y(f)| proportional to |G(f)|



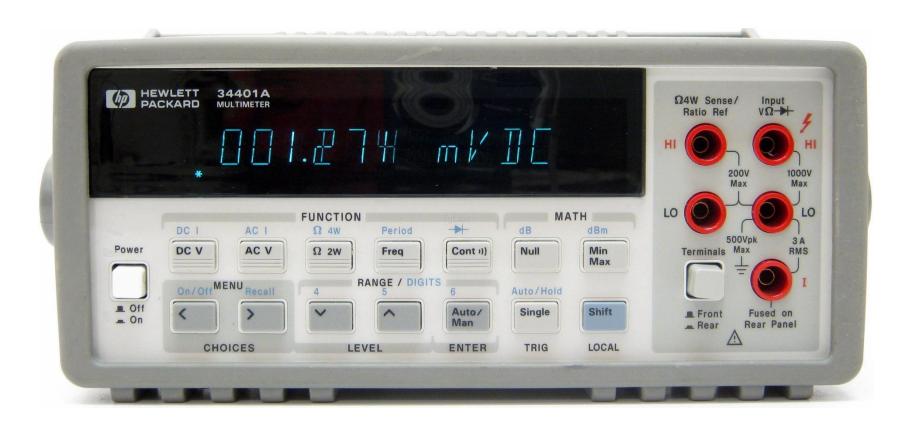
Synchronization output

- Two levels signal: the rising edge of a steep transition coincides with the start
 of a signal period
- Zero mean sinewave → Zero crossing
- Maximum possible slope

'Sync' output → Oscilloscope 'external trigger'



Digital multimeter (DMM)



Measurements of:

- DC and AC voltage
- DC and AC current
- Resistance
- High resolution ADC (up to 24 bits or higher)
- 3 or 5 inputs
 - Positive voltage
 - Negative voltage
 - Current
 - Ω -sense terminal
- Different measurement ranges

DMM resolution

- Resolution: smallest change in a quantity being measured that causes a
 perceptible change in the corresponding indication
- ±1 variation in the least significant digit
- Same quantity of the measured quantity \rightarrow same measurement unit
- Relative resolution

$$\frac{\Delta_X}{X_M}$$
 Λ_X

$$\frac{X}{X_{FS}}$$

DMM number of digits

- Resolution → Number of digits → Uncertainty
- D decimal digits $\to 10^D-1$ maximum displayed value $\to \frac{1}{10^D}$ resolution relative to full scale
- 4-digit DMM \rightarrow 10⁻⁴ resolution relative to full scale value
- Typical full scale values: (0.3, 3, 30, 300), (0.2, 2, 20, 200)
- Still D digits, but the the most significant is not employed to display the maximum value
- $(D-1) + \frac{1}{2}$ DMMs (e.g., $3^{1}/_{2}$, $5^{1}/_{2}$, $6^{1}/_{2}$, $8^{1}/_{2}$)

DC voltage measurements

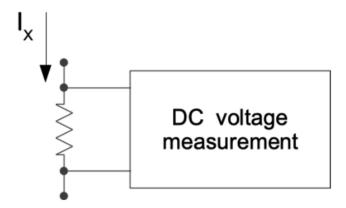
- Wide range of values → attenuators/amplifiers
- Autorange
- Input resistance $R_{in} = 10 M\Omega$
- Differential input configuration with floating ground
- Offset errors → offset compensation
- Autozero (Active by default)

DC current measurements

Current shunt

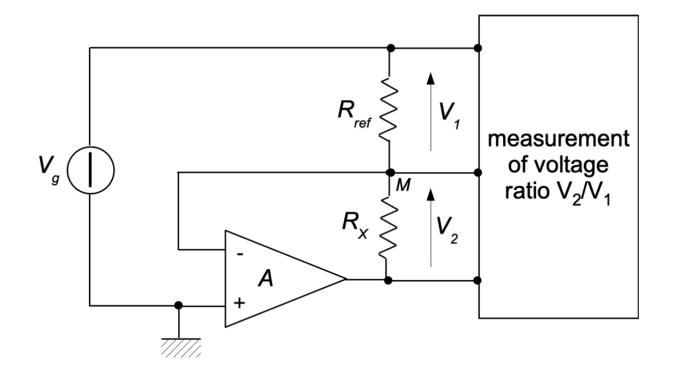
$$I_M = \frac{V_M}{R_{shunt}}$$

- Interruption of a circuit line
- Shunt resistance as low and as constant as possible



Resistance measurements

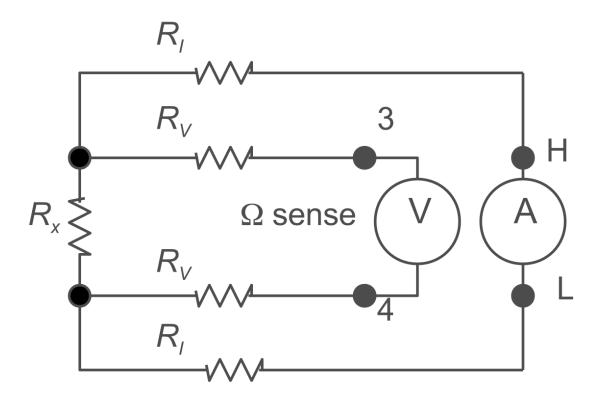
Test current injection



$$R_X = \frac{V_1}{V_2} R_{ref}$$

4-wire resistance measurements

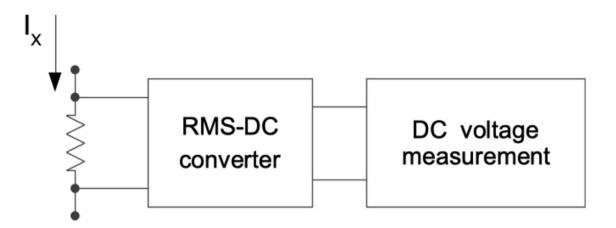
• Avoiding the effects of contact and conductor resistances (some tens of $m\Omega$)



$$R_X = \frac{V_{34}}{I_{HL}}$$
 with $I_{34} = 0$

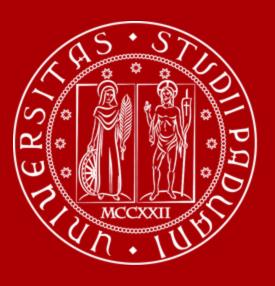
AC measurements

- AC voltage and current Root Mean Square (RMS) value
- Value of a corresponding DC voltage or current that produces the same active power on a resistor
- AC-coupled multimeter
- Other parameters:
 - Peak value X_{PK}
 - Conventional mean value X_M
 - Form Factor (FF) $\rightarrow X_{RMS}/X_{M}$
 - Crest Factor (CF) $\rightarrow X_{PK}/X_{RMS}$



Università degli Studi di Padova AC measurements

x(t)				D = duty cycle
X_{RMS}	$\frac{A_0}{\sqrt{2}}$	$\frac{A_0}{\sqrt{3}}$	A_0	$2A_0\sqrt{D(1-D)}$
X_m	$rac{2A_0}{\pi}$	$rac{A_0}{2}$	A_0	$4A_0[D(1-D]$
X_{pk}	A_0	A_0	A_0	$2A_0\left(\frac{1}{2} + D - \frac{1}{2} \right)$
FF	$\frac{\pi}{2\sqrt{2}} \simeq 1.11$	$\frac{2}{\sqrt{3}} \simeq 1.15$	1	$rac{1}{2\sqrt{D(1-D)}}$
CF	$\sqrt{2}$	$\sqrt{3}$	1	$\frac{\frac{1}{2} + D - \frac{1}{2} }{\sqrt{D(1-D)}}$



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